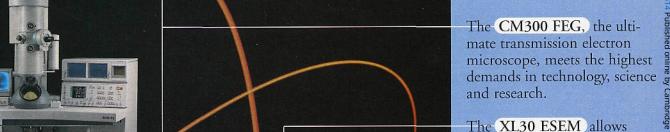
## All in





The XL30 ESEM allows imaging with secondary electrons at adjustable chamber pressures which can be set to 20 torr or higher. Hydrated samples can be investigated in a water vapour environment (100% relative humidity) to prevent changes in the sample caused by dehydration. When using the XL30 ESEM, lengthy preparation of samples is no longer necessary.

The XL30 ESEM and the CM300 FEG are just two examples of Philips Electron Optics' full range of electron microscopes. To find out more about our complete line of SEM and TEM instruments, please contact:

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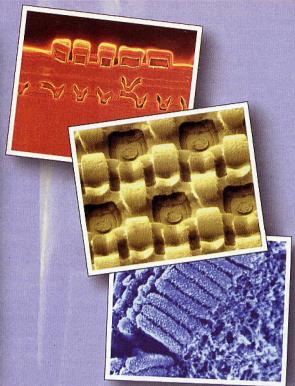




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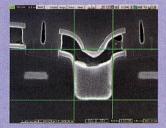
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- Full Automation Allows Users of All Disciplines and Abilities to Take Great Images.
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The new JSM-6340F Computer Controlled Scanning Electron Microscope was designed to be the easiest to use FE-SEM ever.

If you are currently in the market for a high end FE-SEM and need to combine state-of-the-art electronics with the versatility of computer control, we would like to invite you to come to our Applications Facility so that we can prove to you that it really is "As Easy As It Looks".

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